

APJ14N65D (AP65R650)

650V N-Channel Enhancement Mode MOSFET

Description

The APJ14N65D is **CoolFET II** MOSFET family that is utilizing charge balance technology for extremely low on-resistance and low gate charge performance.

APJ14N65F/P/T is suitable for applications which require superior power density and outstanding efficiency

General Features

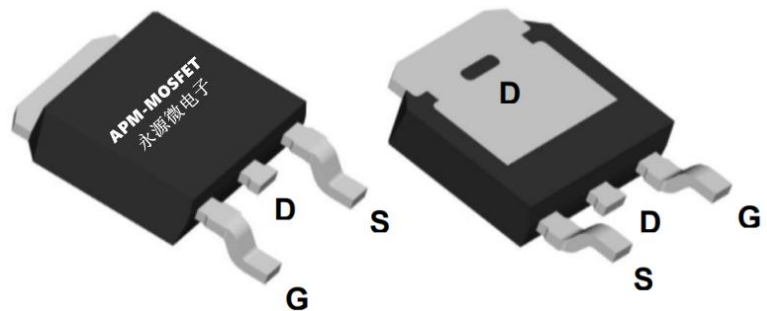
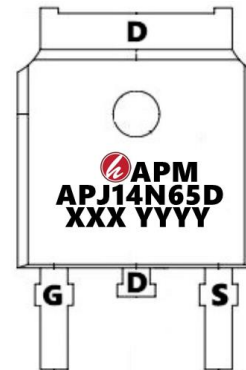
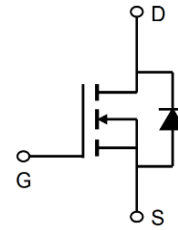
$V_{DS} = 650V$ (Type: 730V) $IDM = 14A$

$R_{DS(ON)} < 650m\Omega$ @ $V_{GS}=10V$ (Type: **560mΩ**)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
APJ14N65D	TO-252-3L	APJ14N65D XXX YYYY	1000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage ($V_{GS} = 0V$)	650	V
I_D	Continuous Drain Current	8	A
I_{DM}	Pulsed Drain Current (note1)	14	A
V_{GS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note2)	125	mJ
P_D	Power Dissipation ($T_c = 25^\circ C$)	25.5	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^\circ C$
R_{thJC}	Thermal Resistance, Junction-to-Case	4.9	$^\circ C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	49	$^\circ C/W$

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain to source breakdown voltage	V _{GS} =0V, I _D =250uA	650	700	--	V
ΔBV _{DSS} / ΔT _J	Breakdown voltage temperature coefficient	I _D =250uA, referenced to 25°C	--	0.7	--	V/°C
IDSS	Drain to source leakage current	V _{DS} =650V, V _{GS} =0V	--	--	1	uA
		V _{DS} =520V, T _C =125°C	--	--	50	uA
IGSS	Gate to source leakage current, forward	V _{GS} =30V, V _{DS} =0V	--	--	100	nA
	Gate to source leakage current, reverse	V _{GS} =-30V, V _{DS} =0V	--	--	-100	nA
VGS(TH)	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250uA	2.5	3.3	4.5	V
RDS(ON)	Drain to source on state resistance	V _{GS} =10V, I _D =3.2A	--	560	650	mΩ
Ciss	Input capacitance	V _{GS} =0V, V _{DS} =100V, f=1MHz	--	438	--	pF
Coss	Output capacitance		--	19.5	--	
Crss	Reverse transfer capacitance		--	1.32	--	
td(on)	Turn on delay time	V _{DS} =400V, I _D =3.2A, R _G =4.7Ω, V _{GS} =10V	--	84.8	--	ns
tr	Rising time		--	25.2	--	
td(off)	Turn off delay time		--	227.6	--	
tf	Fall time		--	26.8	--	
Q _g	Total gate charge	V _{DS} =480V, V _{GS} =10V, I _D =3.2A	--	11	--	nC
Q _{gs}	Gate-source charge		--	2.1	--	
Q _{gd}	Gate-drain charge		--	5.6	--	
IS	Continuous source current	Integral reverse p-n Junction diode in the MOSFET	--	--	11	A
ISM	Pulsed source current		--	--	44	A
VSD	Diode forward voltage drop.	I _S =3.2A, V _{GS} =0V	--	0.7	1.5	V
T _{rr}	Reverse recovery time	I _S =3.2A, V _{GS} =0V, V _{DD} =400V, di _F /dt=100A/us,	--	313	--	ns
Q _{rr}	Reverse recovery Charge		--	0.877	--	uC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
2. The EAS data shows Max. rating . L=0.5mH, I_{AS} =3.2A, V_{DD} =50V, R_G=25Ω
3. The test condition is Pulse Test: I_{SD} ≤ I_D, di/dt = 100A/us, V_{DD} ≤ BVDSS, Starting at T_J =25°C
4. The power dissipation is limited by 150°C junction temperature
5. The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.

Typical Characteristics

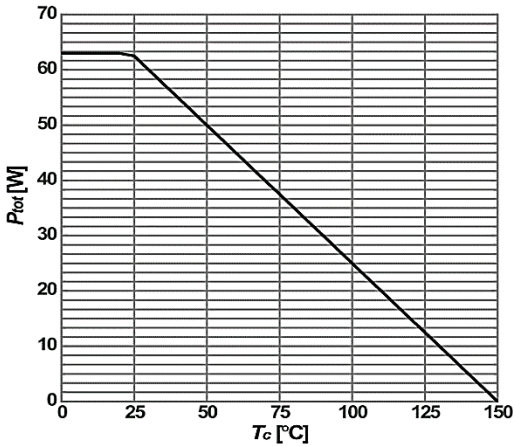


Figure1: Power dissipation (Non FullPAK)

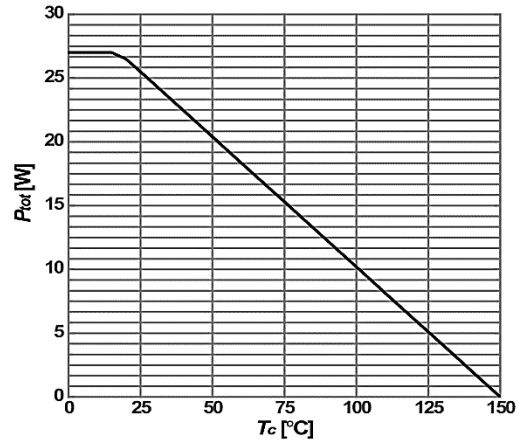


Figure2: Power dissipation (FullPAK)

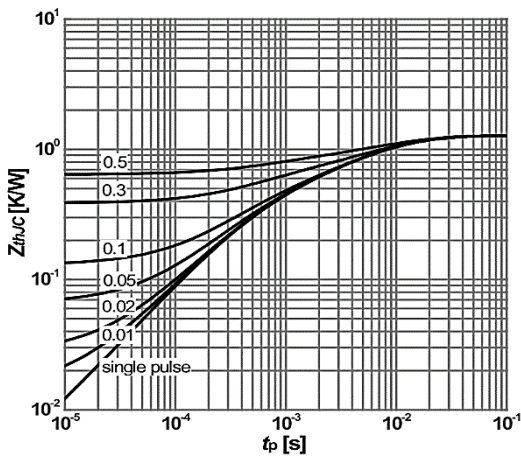


Figure3:Max. transient thermal impedance
 $Z_{thJC}=f(t_p)$; parameter: $D= t_p/T$

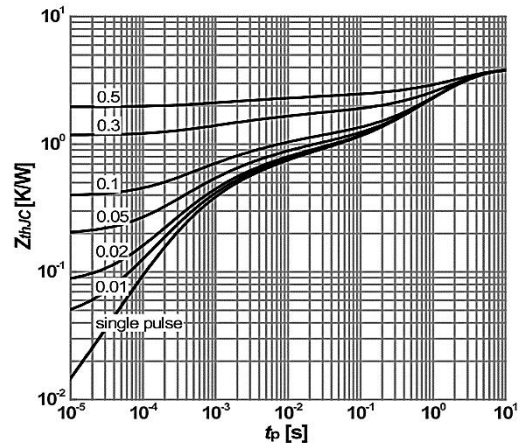


Figure4:Max. transient thermal impedance
 $Z_{thJC}=f(t_p)$; parameter: $D= t_p/T$

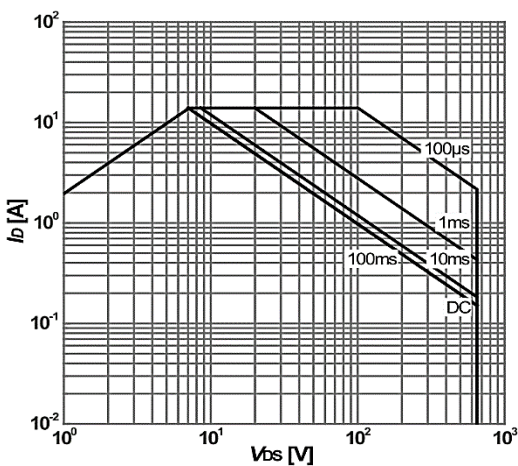


Figure5: Safe operating area (Non FullPAK)
 $I_D=f(V_{DS})$; $T_J=25^\circ\text{C}$; $D=0$; parameter: t_p

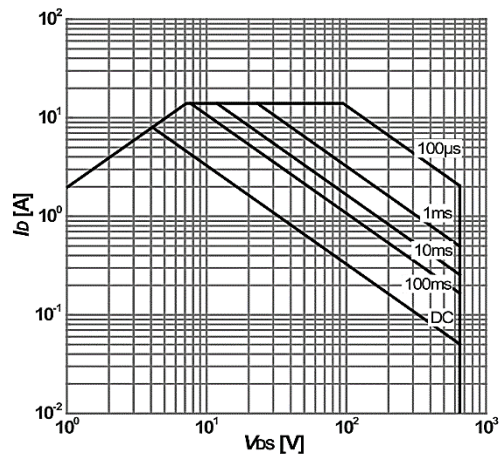


Figure6: Safe operating area (FullPAK)
 $I_D=f(V_{DS})$; $T_J=25^\circ\text{C}$; $D=0$; parameter: t_p

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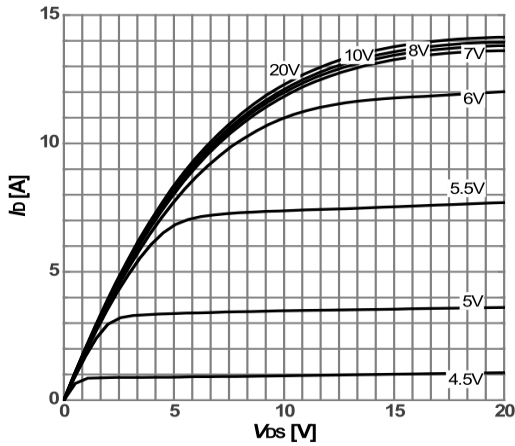


Figure 7: Typ. output characteristics
 $I_D=f(V_{DS}); T_j=25^\circ\text{C};$ parameter: V_{GS}

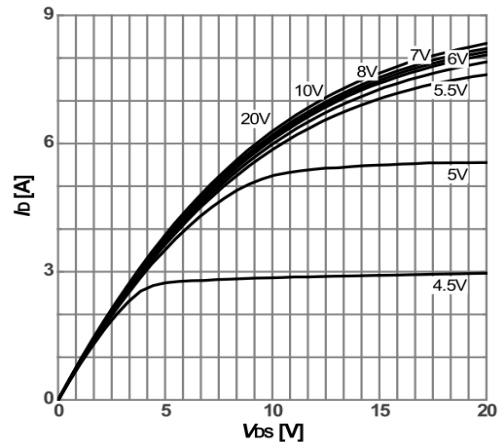


Figure 8: Typ. output characteristics
 $I_D=f(V_{DS}); T_j=125^\circ\text{C};$ parameter: V_{GS}

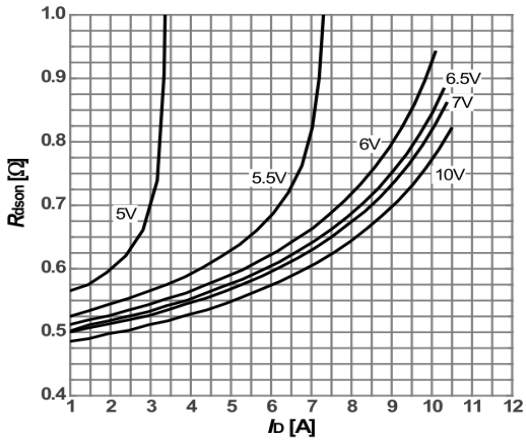


Figure 9: Typ. drain-source on-state resistance
 $R_{DS(on)}=f(I_D); T_j=25^\circ\text{C};$ parameter: V_{GS}

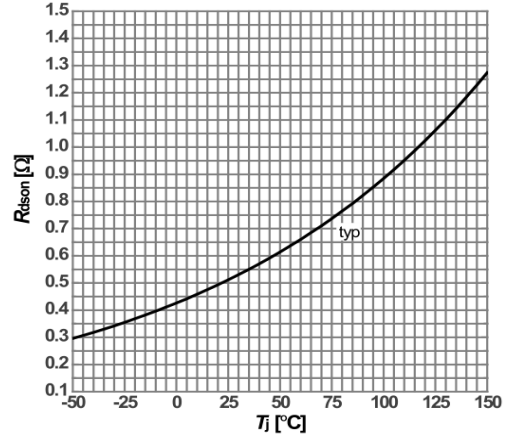


Figure 10: drain-source on-state resistance
 $R_{DS(on)}=f(T_j); I_D=3.2\text{A}; V_{GS}=10\text{V}$

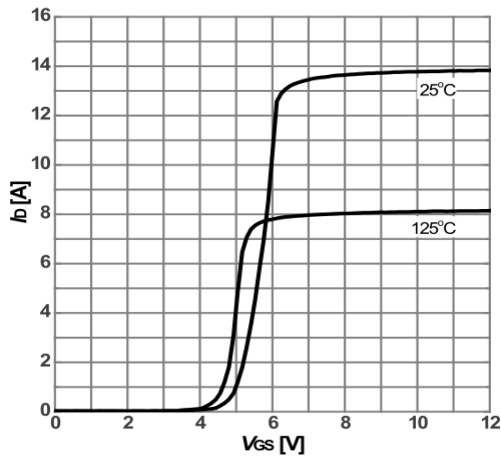


Figure 11: Type. transfer characteristics
 $I_D=f(V_{GS}); V_{DS}=20\text{V};$ parameter: T_j

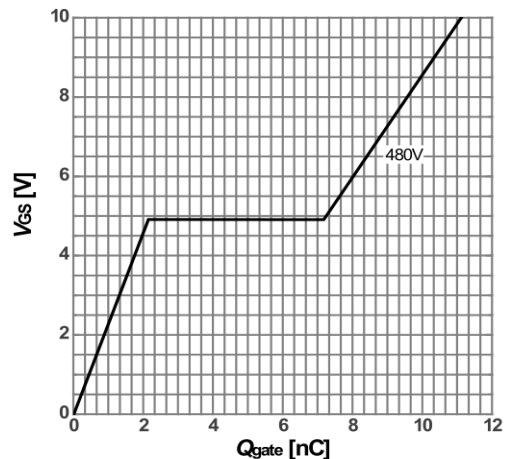
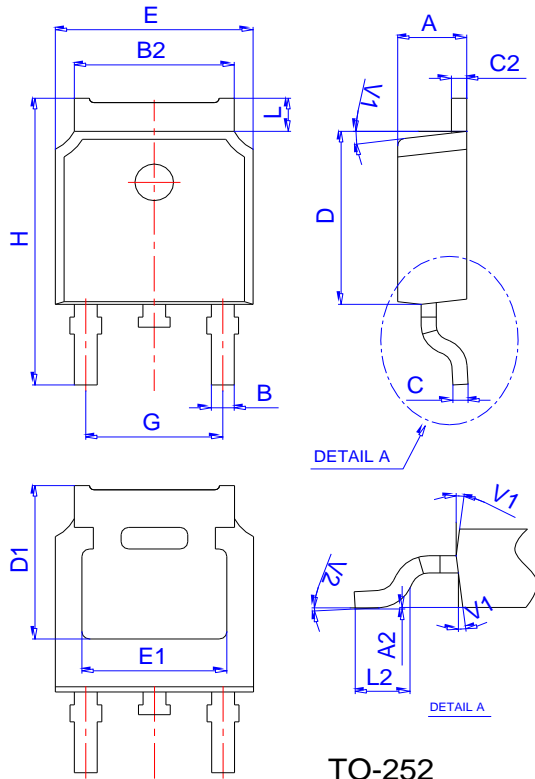


Figure 12: Type. gate charge
 $V_{GS}=f(Q_{gate}); I_D=3.2\text{A}$ pulsed; $V_{DS}=480\text{V}$

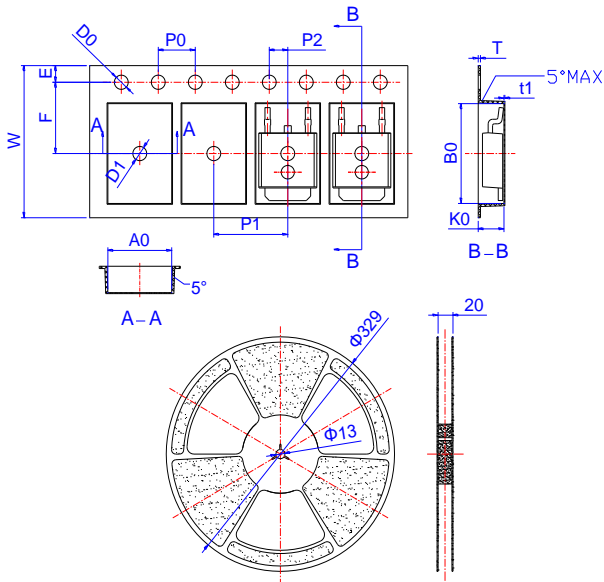
Package Mechanical Data: TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

TO-252

Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

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Edition	Date	Change
Rve1.0	2018/1/31	Initial release

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